

Freeform Search

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Term:

L11 not L9

Display: Documents in Display Format: Starting with Number Generate: ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image

Search

Clear

Interrupt

Search History

DATE: Monday, December 20, 2004 [Printable Copy](#) [Create Case](#)

Set Name Query

side by side

Hit Count Set Name

result set

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

<u>L12</u>	L11 not L9	93	<u>L12</u>
<u>L11</u>	L8 and ((monitor\$3 or inspect\$4 or measur\$5 or map\$4) with (dos\$3 or implant\$5))	108	<u>L11</u>
<u>L10</u>	L8 and ((monitor\$3 or inspect\$4 or measur\$5 or map\$4) with (dos\$3 or implant\$5))	108	<u>L10</u>
<u>L9</u>	L8 and (wafer with map\$4)	27	<u>L9</u>
<u>L8</u>	L6 and (surface with reflectivity)	469	<u>L8</u>
<u>L7</u>	L6 and (surface with reflectivity)	0	<u>L7</u>
<u>L6</u>	(wafer or semiconductor) same (ion with implant\$6)	54532	<u>L6</u>
<u>L5</u>	5333049.pn.	2	<u>L5</u>
<u>L4</u>	L3 and (incoherent or non-destructive)	23	<u>L4</u>
<u>L3</u>	wafer and (relative adj reflectivity)	90	<u>L3</u>
<u>L2</u>	(relative with reflectivity with wafer)	37	<u>L2</u>
<u>L1</u>	(map with relative with reflectivity with wafer)	0	<u>L1</u>

END OF SEARCH HISTORY